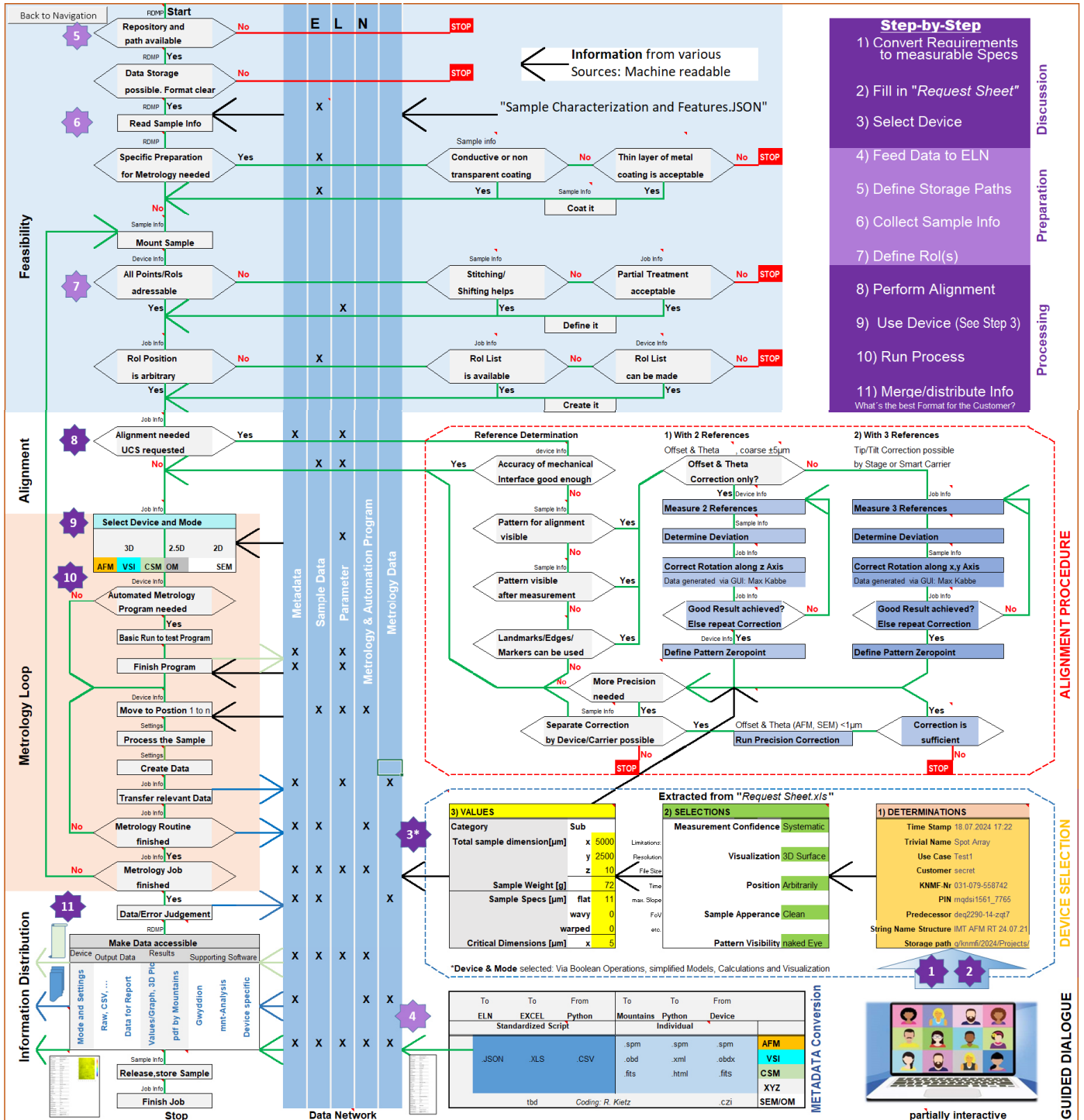


Implementing Correlated Characterization in Standardized Surface Metrology Flow - ELN is the Backbone for Data Management

Richard Thelen^{1,2}, Maximilian Kabbe^{1,2}, Hendrik Hölscher¹, Jan G. Korvink¹, Jürgen Brandner^{1,2}

¹ Institute of Microstructure Technology (IMT) Karlsruhe Institute of Technology, Eggenstein-Leopoldshafen

² Karlsruhe Nano Micro Facility KNMFi, Karlsruhe Institute of Technology, Eggenstein-Leopoldshafen, Germany



Decision Tree.xls

richard.thelen@kit.edu

Karlsruhe Institute of Technology
Institute of Microstructure Technology
Hermann-von-Helmholtz-Platz 1
76344 Eggenstein-Leopoldshafen

Institute of Microstructure Technology 